



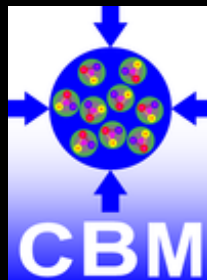
2016, Darmstadt

“Vacuum-Compatible, Ultra-Low Material Budget MVD for the CBM Experiment : Group Report”

Michal Koziel

On behalf of CBM-MVD group.

koziel@physik.uni-frankfurt.de



CBM-MVD related contributions



This talk

M. Koziel: “Vacuum-Compatible, Ultra-Low Material Budget MVD for the CBM Experiment.”

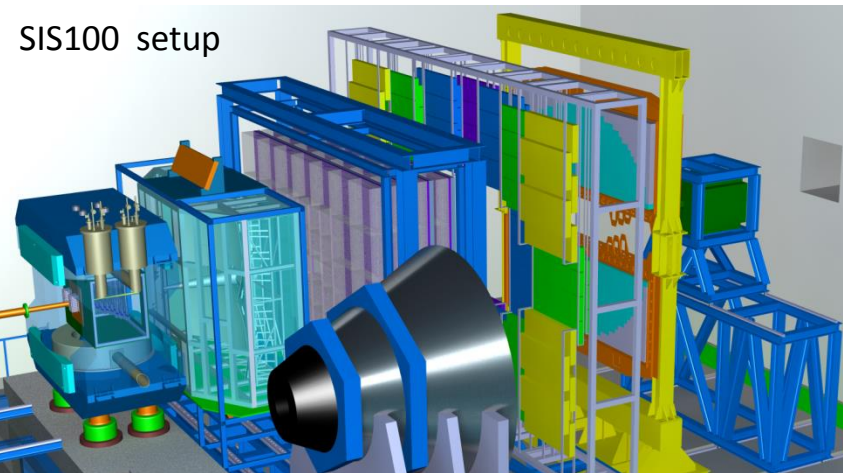
Monday 14:00 HK 7.1

- M. Deveau: “On drift fields in CMOS Monolithic Active Pixel Sensors.”
Monday 14:45 HK 7.3
- Erik Krebs: “Background rejection in dilepton analysis with CBM-MVD”
Monday 17:45 HK 10.5
- D. Doering / M.Deveau: “Ein Röntgenspektrometer auf der Basis von hochspannungstauglichen CMOS-Sensoren mit hochdotiertem Dopinigradienten im aktiven Medium.”
Tuesday 14:30 HK 21.2
- B. Linnik: “Status of the radiation hardness of CMOS Monolithic Active Pixels Sensors for the CBM experiment.”
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- T. Bus: “Strahlenschäden in dotiertem Silizium aufgrund Neutroneneinfangs Bor als Erweiterung des NIEL-Modells.”
Wednesday 18:30 HK 45.49
- P. Klaus: “Thin and Reliable Connectivity for the CBM-MVD”
Thursday 18:00 HK 60.7

Outline

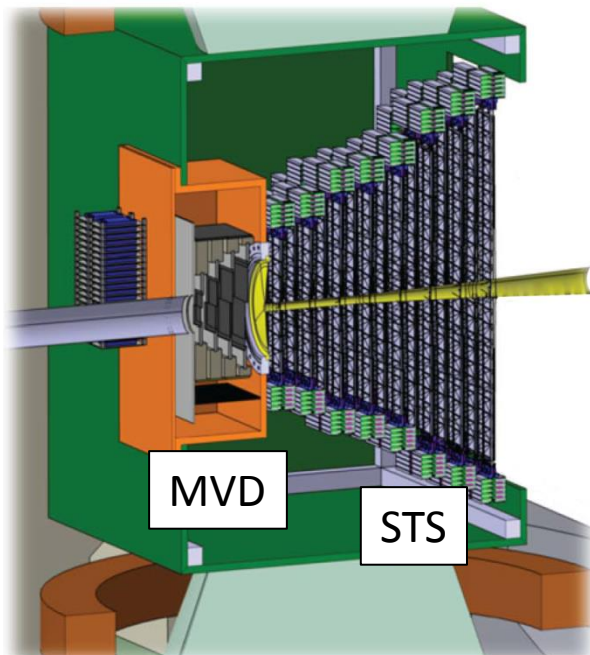
- The CBM-MVD: reminder
- Simulations
 - Tracking performance
 - Background rejection in dielectron analysis
- Sensor development
- PRESTO Project
- Summary

The CBM Micro Vertex Detector: Reminder p.1



CBM-MVD :

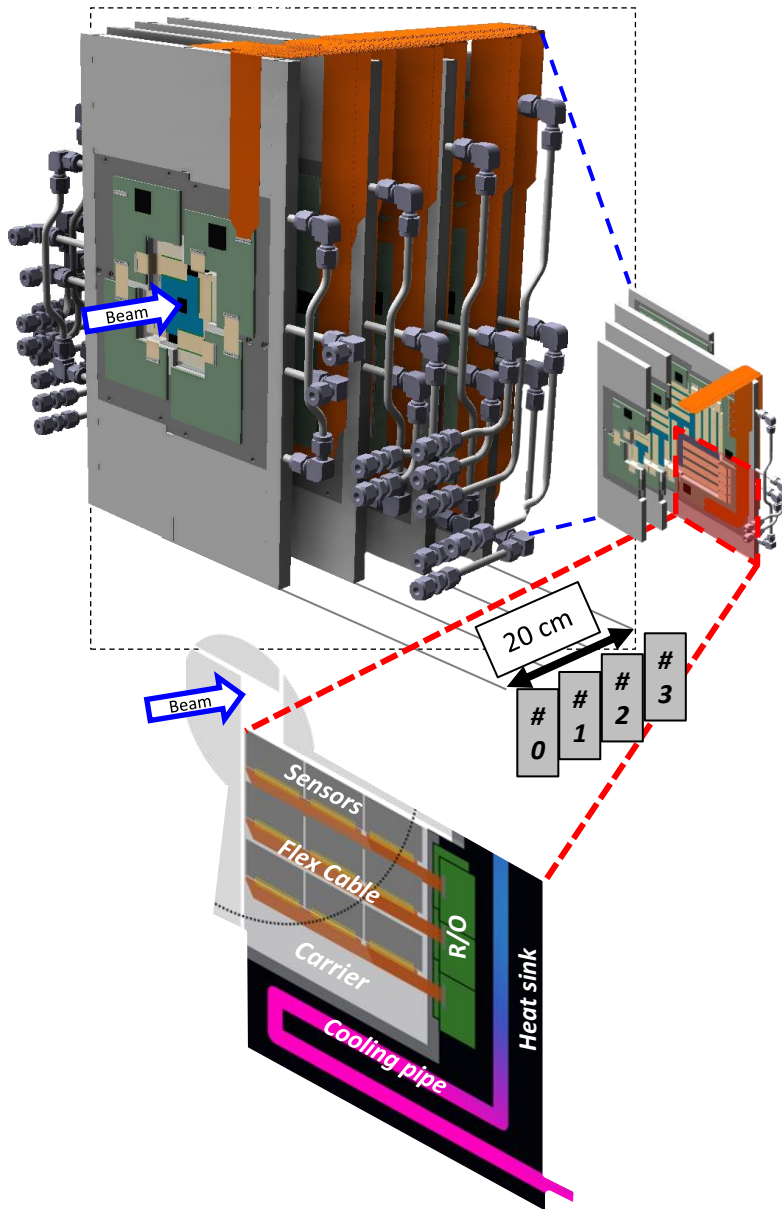
- Improve secondary vertex resolution (open charm)
- Tracking of low-momentum particles
- Background rejection in di-electron measurements
- Hosts highly granular silicon pixel sensors featuring low material budget, fast read-out, excellent spatial resolution and robustness to radiation environment.



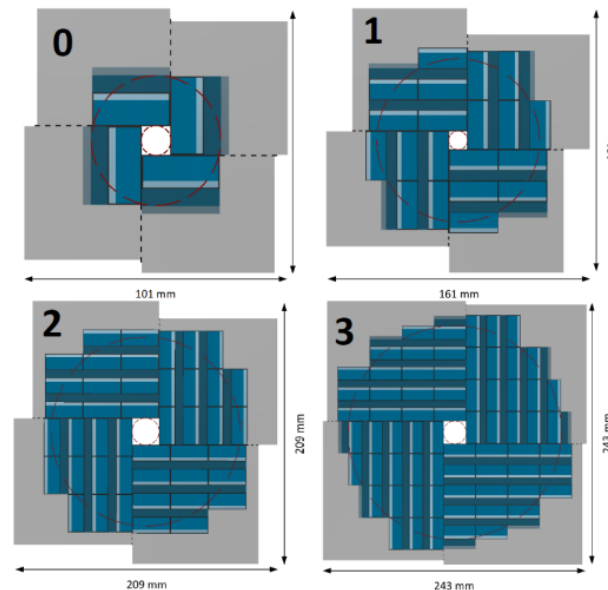
Required performances (SIS-100)

Radiation tolerance	$> 10^{13} n_{eq}/cm^2$ & > 1 Mrad
Read-out speed	> 30 kframes/s
Intrinsic resolution	5-10 μm - physics case driven
Operation in vacuum & magnetic field	
Support & cooling	Material budget $\sim 0.3 \% x/X_0$ Double-sided sensor integration

The CBM Micro Vertex Detector: Reminder p.2

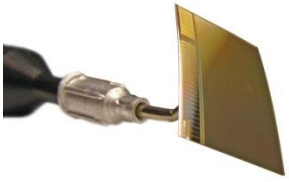


Station		Radius [mm]		Details	
No.	Distance from target [mm]	Inner	Outer	Min. # of 3x1 cm sensors	Carrier material
0	50	5.5	25	8	CVD diamond
1	100	5.5	50	36	CVD diamond
2	150	8.3	75	78	TPG
3	200	11	100	128	TPG



Minimum geometrical acceptance shown

CBM-MVD: integration challenge



4 stations populated with sensors

- Sensor development
- Sensor commissioning

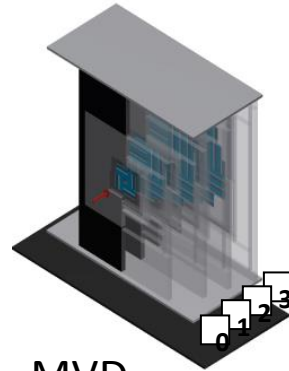


Sensor support (CVD-Diamond & TPG)



Readout & services

- R/O electronics
- Flex Print Cables (FPC)



MVD mechanics

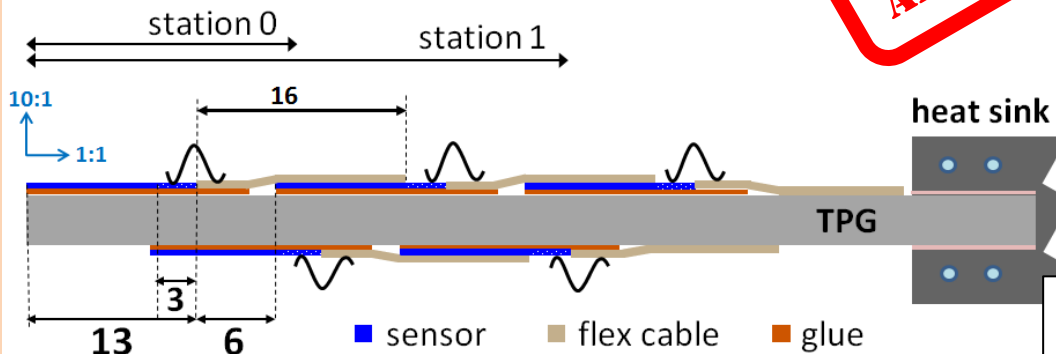
- Jigs
- Dispensing tools
- Procedure

INTEGRATION

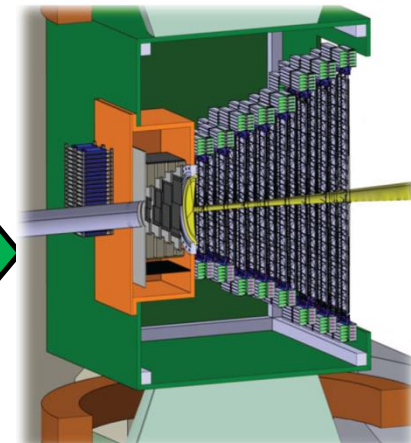
- Quality assessment
- Metrology
- Alignment

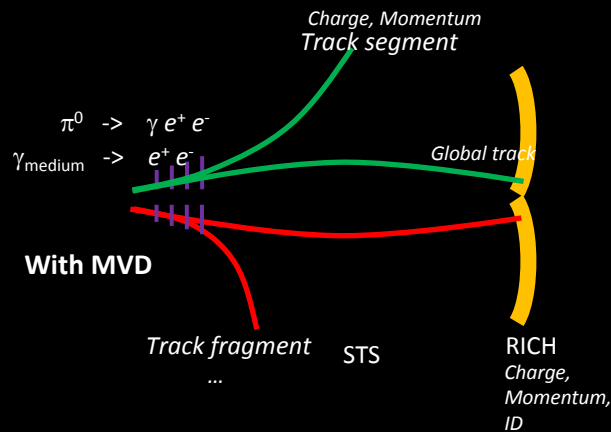
VACUUM APPROVED

Geometrical acceptance:



QUADRANTS





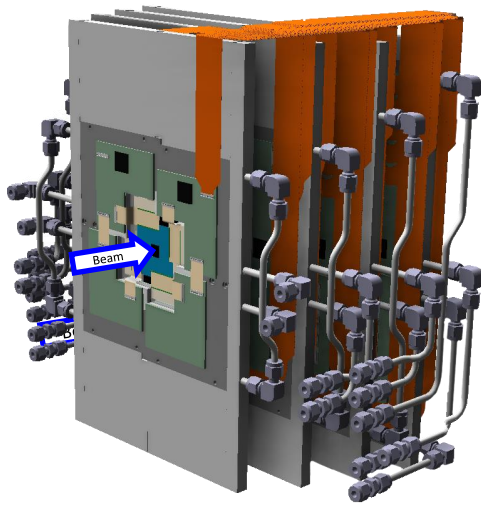
SIMULATIONS

Performance & Physics Case Studies

Erik Krebs: **"Background rejection in dilepton analysis with CBM-MVD"**

Monday 17:45 HK 10.5

MC simulations => MVD+STS tracking capability



FAIR
ROOT

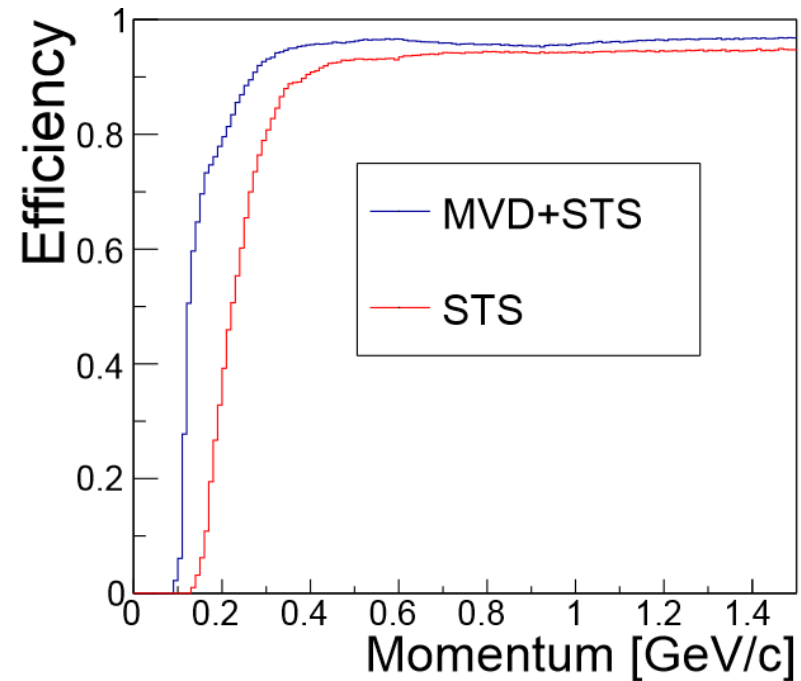
Monte Carlo simulations

Setup = 4 MVD + 8 STS stations

Primary tracks considered

Studied:

- Impact parameter resolution
- Momentum resolution
- Tracking efficiency
- For particles with momentum smaller than 0.5 GeV/c

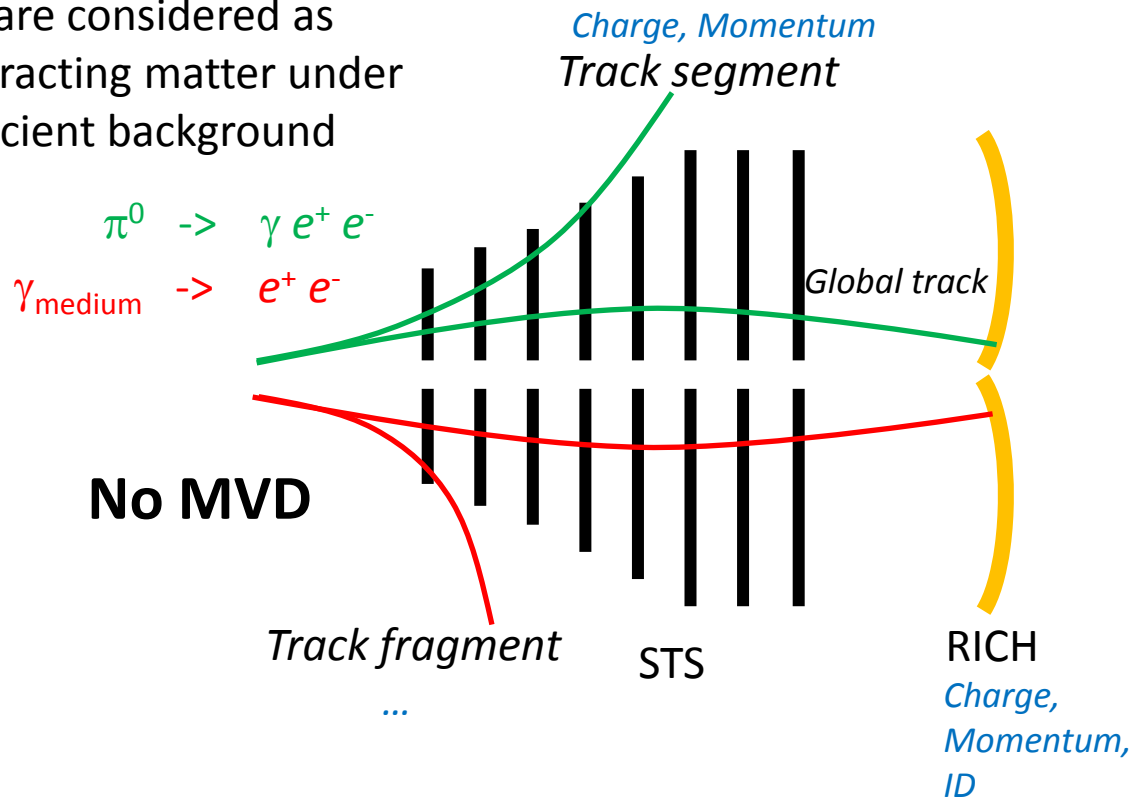


Conclusion: MVD improves the CBM tracking capability due to added value, that is spatial resolution and geometrical acceptance.

Background rejection with MVD

The light vector mesons ρ , ω and ϕ are considered as excellent probes of the strongly interacting matter under extreme conditions... but rare \rightarrow efficient background rejection.

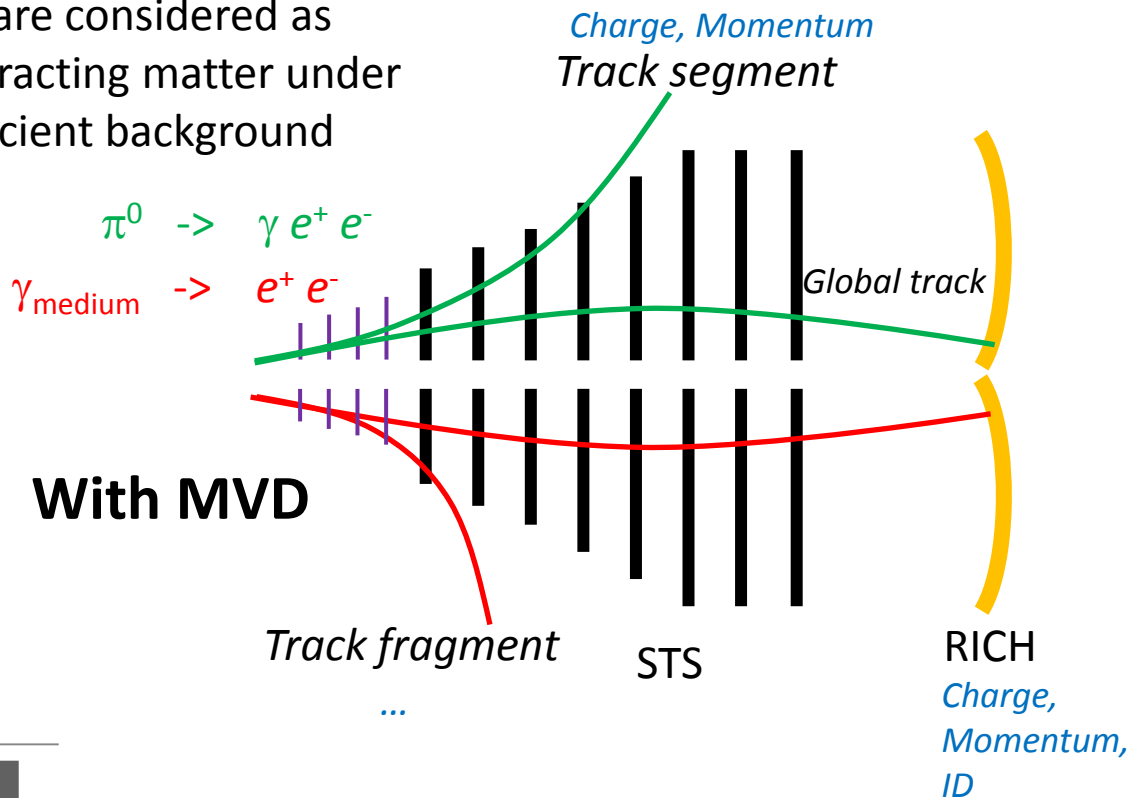
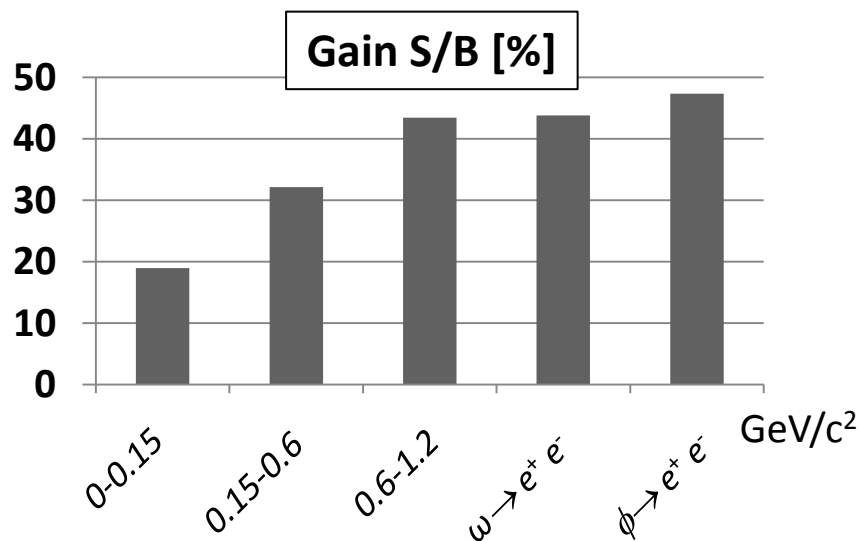
Single electron or positron tracks from incompletely detected γ -conversions and Dalitz decays of π^0 -mesons are the most abundant source contributing to the combinatorial background.



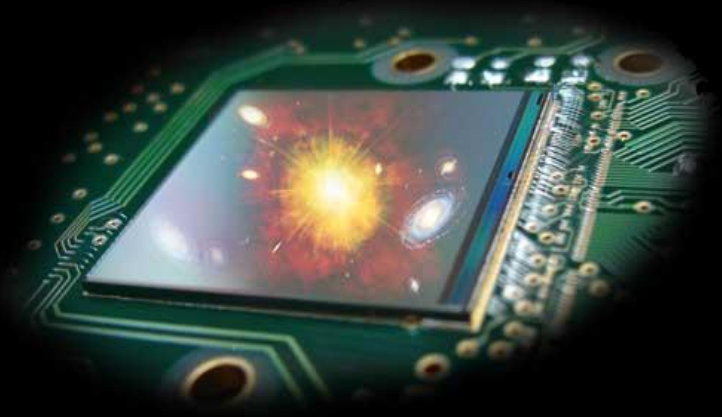
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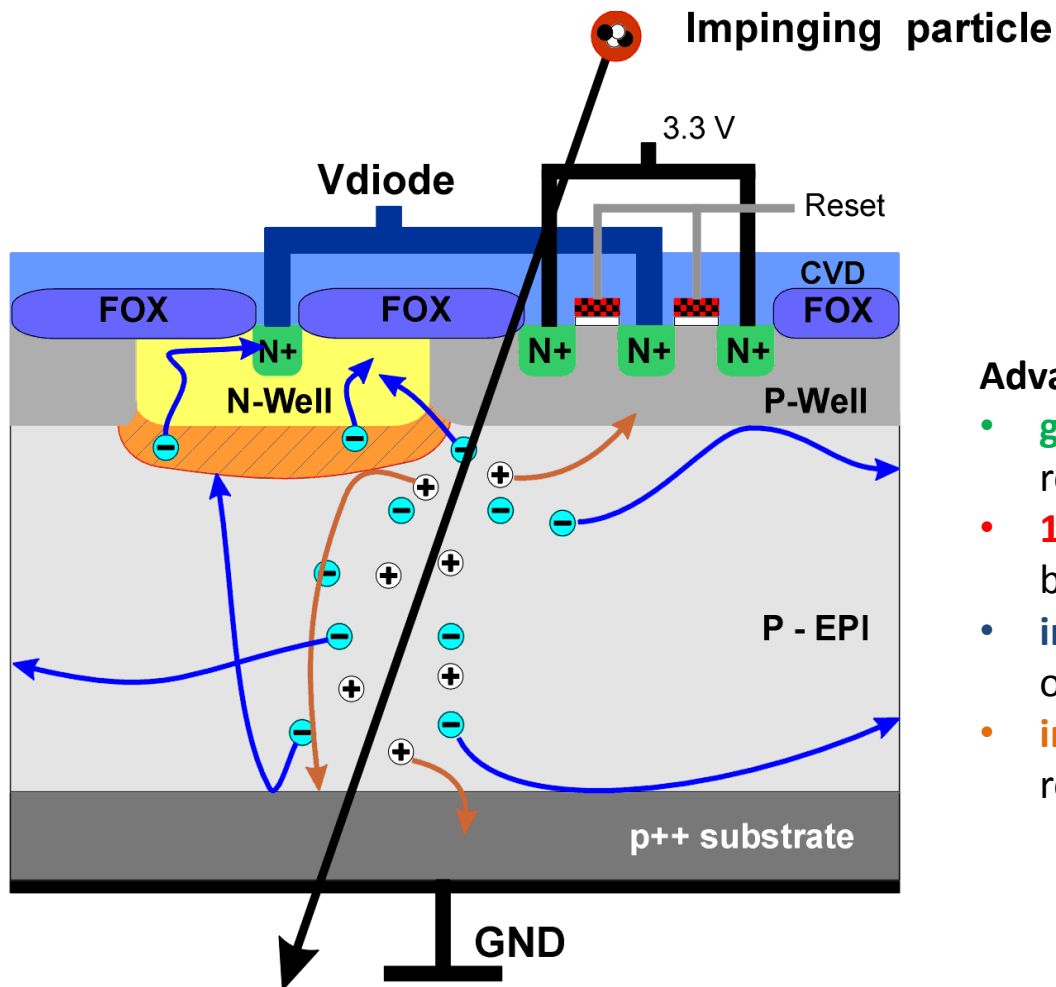
Tracking of low momentum tracks, helps to suppress background (mainly from conversion) as being e.g. well established by HADES collaboration.



SENSOR DEVELOPMENT

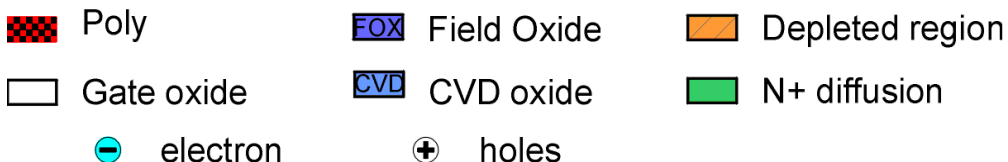
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CMOS Pixel Sensors (CPS)



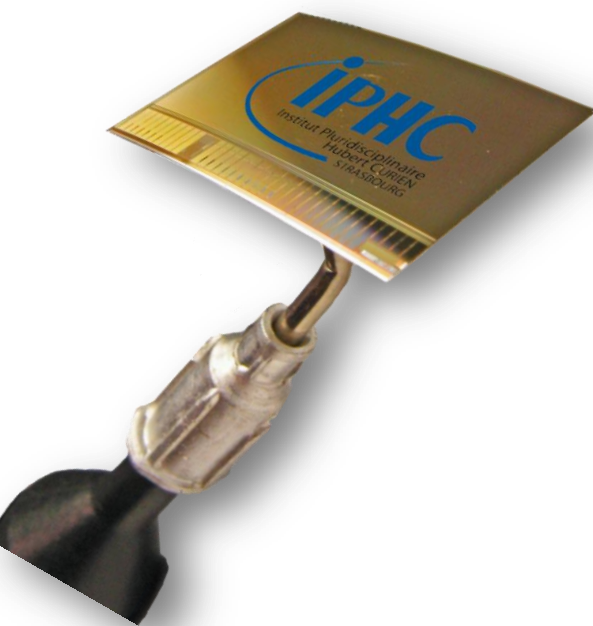
Advantages of CMOS sensors:

- **granularity**: pixels of $10 \times 10 \mu\text{m}$, high spatial resolution
- **10-20 μm thick sensing volume**: low material budget (typically $50 \mu\text{m}$ Si)
- **in-chip signal processing**: compact sensors with on-board intelligence, e.g. data sparsification
- **in addition**: cost, multi-project run frequency, room temperature operation, potentially HR EPI



CBM-MVD sensor specification

PRELIMINARY !!!

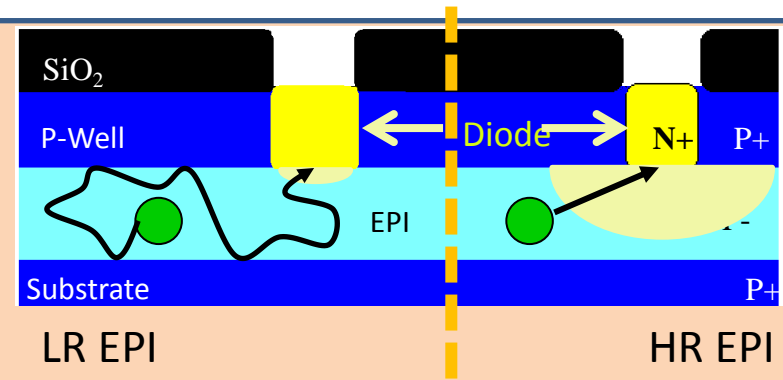
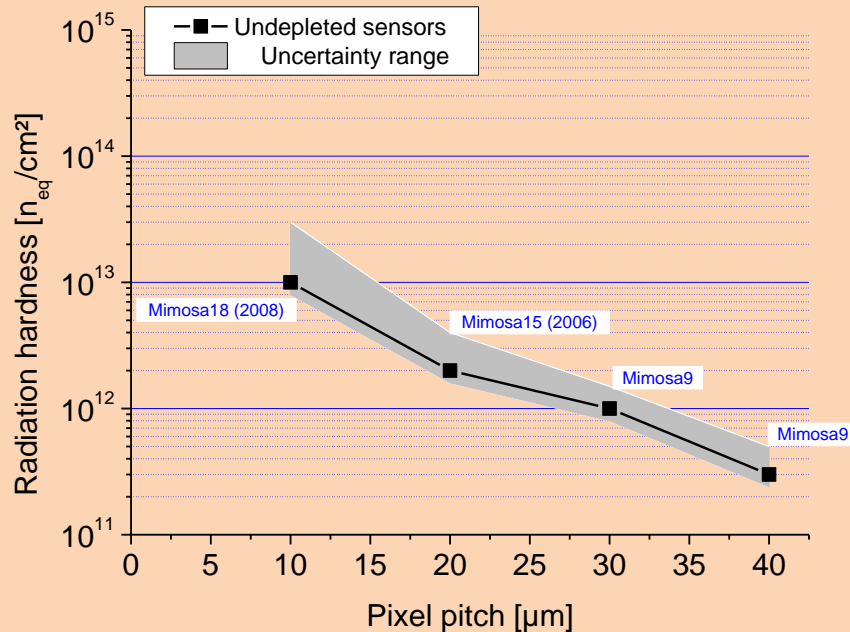


PARAMETER	Baseline
Spatial resolution	~ 5 μm
Maximum power dissipation (full occupancy) [mW/cm^2]	< 200
→ Reduced rate, Station 2-3	< 350
→ Full rate, Station 0-1	
Pixel pitch	~30 x 30 μm^2
Operation temperature [$^{\circ}\text{C}$]	-40 to +30
Operation temperature gradient on sensor [K/cm]	5
Radiation doses [n_{eq}/cm^2]	
@ -20 $^{\circ}\text{C}$	3×10^{13}
@+30 $^{\circ}\text{C}$	1×10^{13}
Radiation doses [Mrad]	
@ -20 $^{\circ}\text{C}$	3 Mrad
@+30 $^{\circ}\text{C}$	1 Mrad
Radiation doses [HI/cm^2]	10^{10} ? High uncertainty
Radiation dose (gradient)	100%
Readout time (μs)	~10
Average hit rate ($1/\text{mm}^2/\text{s}$)	1.5×10^5
Peak hit rate ($1/\text{mm}^2/\text{s}$)	7×10^6
Maximum Data rate (Gbps/cm^2)	~1.6
Minimum Data rate (Gbps/cm^2)	0.16
Encoding	24bit/hit

PARAMETER	Baseline
Efficiency	
→ New	> 99%
→ End of lifetime	~99%
Fake hit rate	
→ New	10^{-5}
→ End of lifetime	10^{-4}
Data interface	320 Mbps
Minimum number of data lines/sensor	
I/O Standard	GBT-comp.
Bonding technology	Wedge
Bias voltage mismatch tolerance	0.3V
Variation in currents	5%
Slow control	
Clock down	Factor 2 (Uncertain)
Sensor surface (sensitive)	$3 \times 1 \text{ cm}^2$
Sensor surface (insensitive)	$3 \times 0.3 \text{ cm}^2$
Thickness	50 μm
ESD - Protection	
Pads for probe testing	
Unique ID for sensors	
Alignment markers	
Temperature sensor	

How to improve radiation tolerance of CPS

How to improve the non-ionizing hardness:



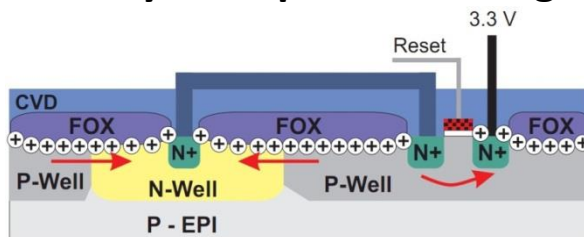
Aim for a larger depletion zone !!!

- Diffusion -> drift in electric field
 - Doping profile
 - Higher depletion voltage



Calls for CMOS processes providing a High Resistivity epitaxial layer.

The way to improve ionizing hardness:



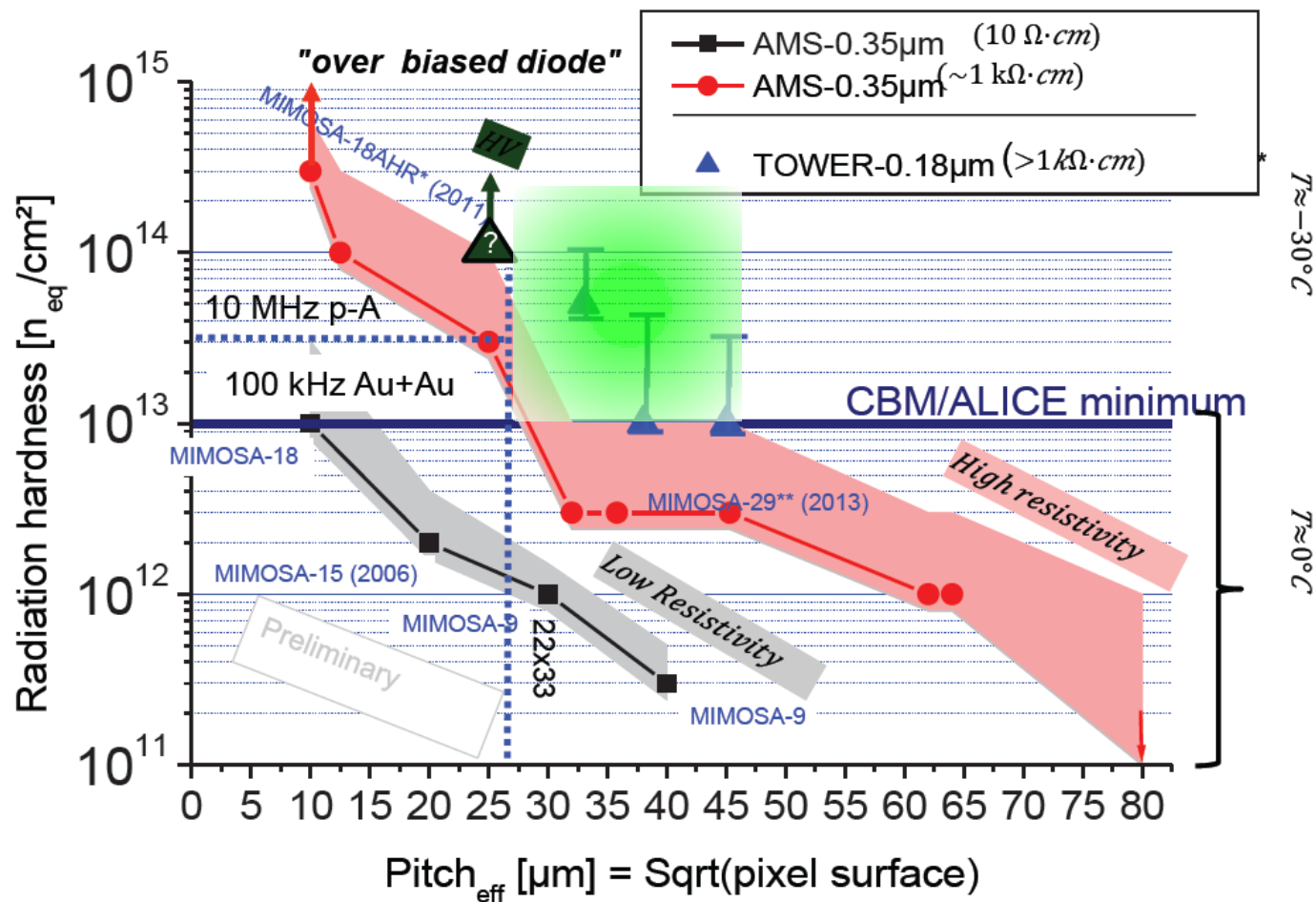
Investigate processes with small feature size, 0.18 μm and below.

Radiation hardness: 2015 achievements

Aim: investigate the radiation hardness of the JAZZ-TOWER 0.18 μm CMOS process

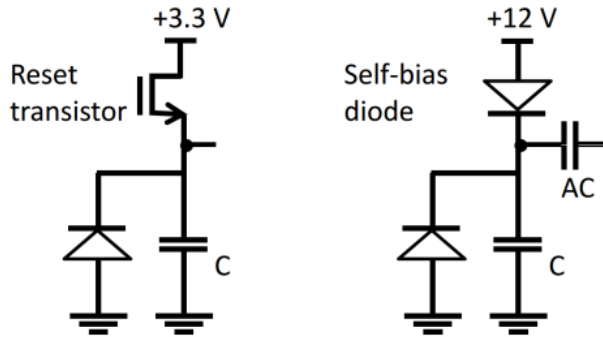
Key point: a high-resistivity ($> 1\text{k}\Omega\cdot\text{cm}$) EPI (HR-EPI) layers with different doping profiles

Outcome: top radiation tolerance for HR-EPI featuring gradient doping profile (publication during write-up)

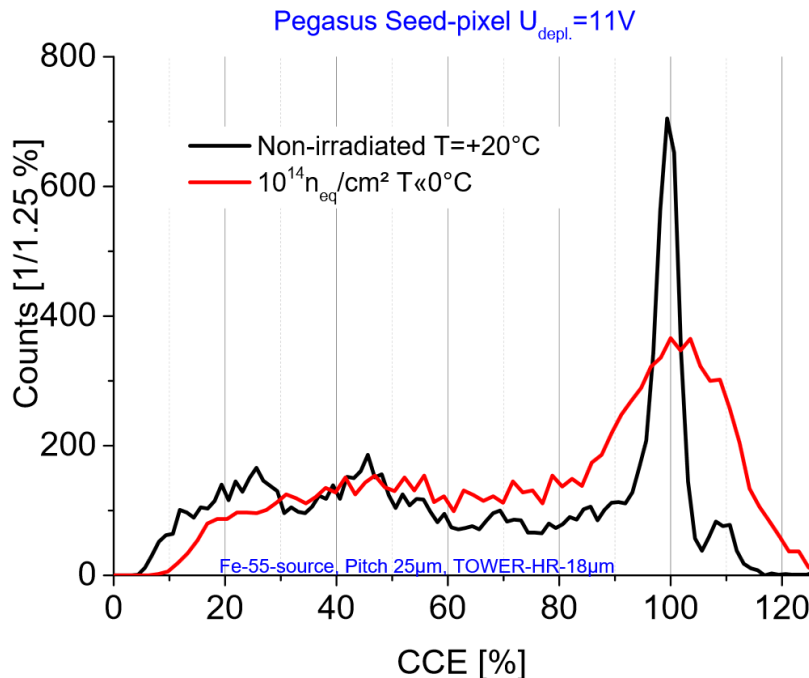


Radiation hardness: 2015 achievements

Towards fully-depleted CMOS pixel sensors: PEGASUS sensor



Aim: Design, manufacture and study the sensor with pixels powered from higher (~ 12.5 V) than standard (0.6-2.8 V) bias voltage.



Outcome: High bias voltage increases the size of the depleted volume to almost (?) full epitaxial layer thickness.

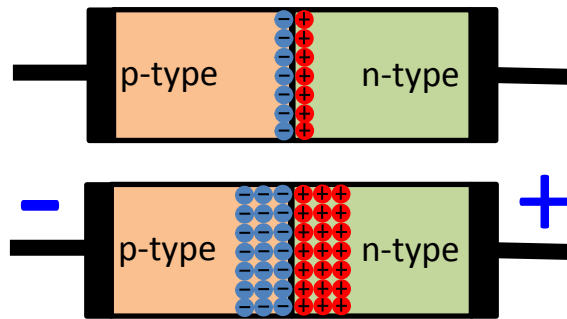


D.Doering et al., "CMOS-sensors for energy-resolved X-ray imaging"

<http://dx.doi.org/10.1088/1748-0221/11/01/C01013>

Why we do not deplete CMOS Pixel Sensors ?

Theory



$$d = \sqrt{\frac{2\epsilon\epsilon_0}{e} + \left(\frac{1}{N_A} + \frac{1}{N_D}\right) (U_{bi} - U)} \sim \sqrt{U_{depl}}$$

$$N_A = 10^{18} / \text{cm}^3$$

$$N_D = 10^{12} / \text{cm}^3$$

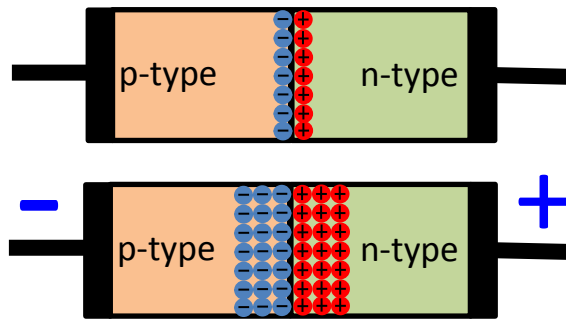
$$U_{depl} = -0.6 \text{ V}$$

$$d = 30 \mu\text{m}$$

**...but full CMOS HR-EPI
depletion at 0.6 V
never observed...**

Why we do not deplete CMOS Pixel Sensors ?

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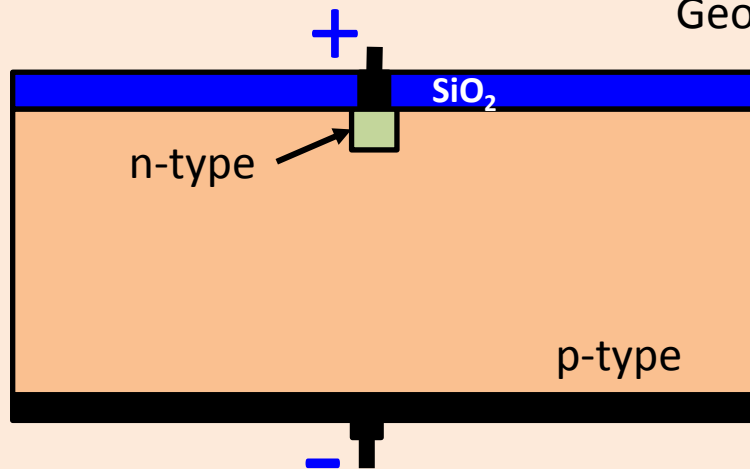
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$$U_{depl} = -0.6 \text{ V}$$

$$d = 30 \mu\text{m}$$

...but full CMOS HR-EPI depletion at 0.6 V never observed...

Reality



Geometry of a real pixel does not fit



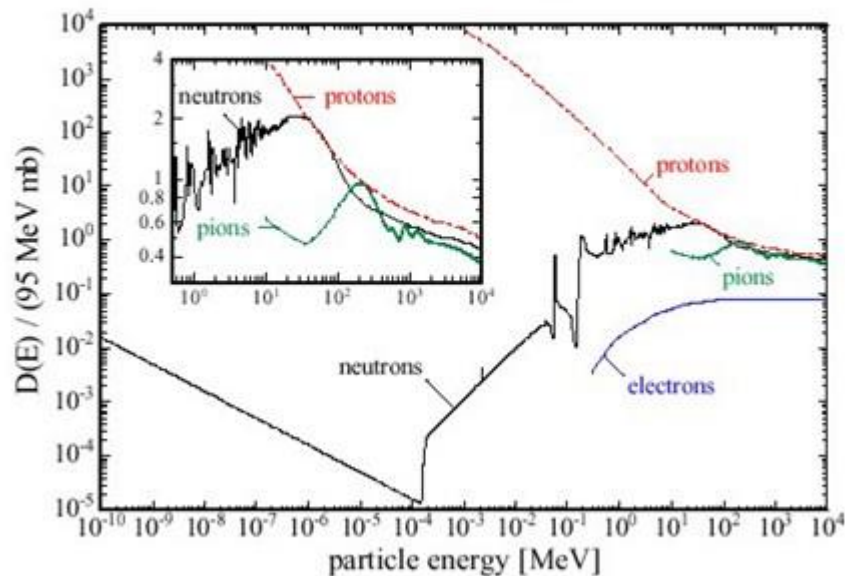
$$d_{CMOS} \sim \sqrt[6]{U_{depl}}$$

M. Deveau: "On drift fields in CMOS Monolithic Active Pixel Sensors."

Monday 14:45 HK 7.3

On the NIEL scaling for low-energy neutrons

Displacement damage functions



According to NIEL (non-ionizing energy loss) scaling, any particle fluence can be reduced to an equivalent 1 MeV neutron fluence producing the same bulk damage in a specific semiconductor. The scaling is based on the hypothesis that generation of bulk damage is due to non-ionizing energy transfers to the lattice.



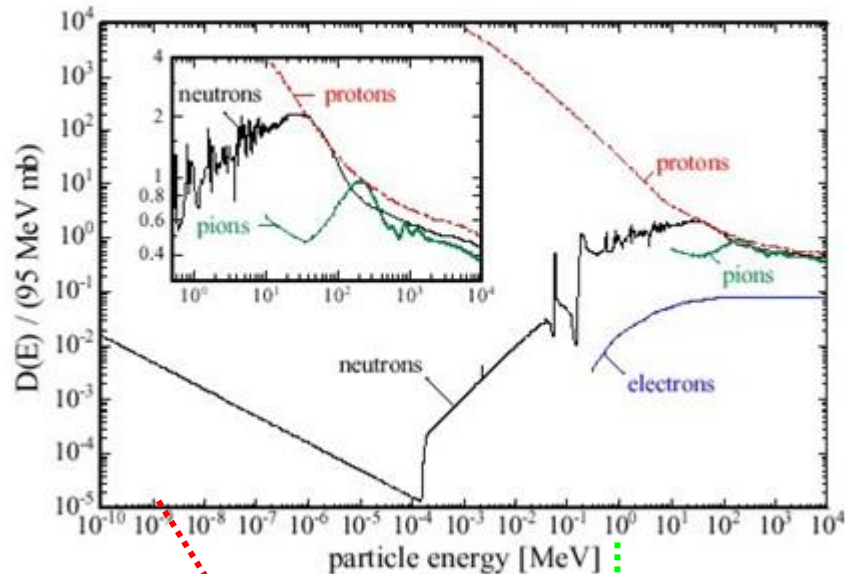
?

Radiation from this process to be considered

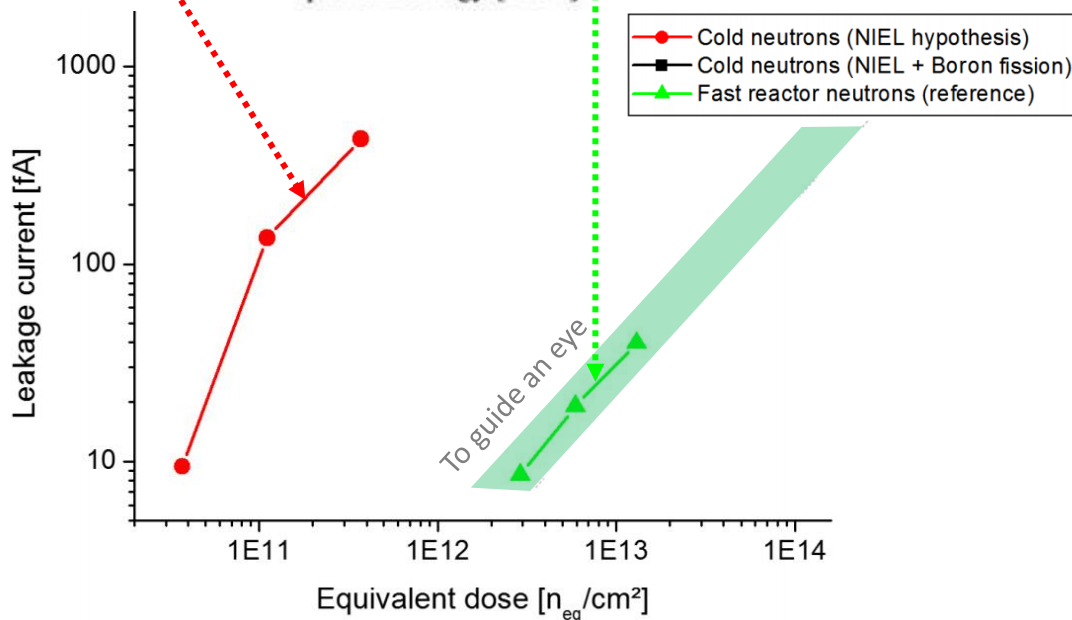
No problem if P-doping $\ll 10^{15}\text{cm}^3$

On the NIEL scaling for low-energy neutrons

Displacement damage functions

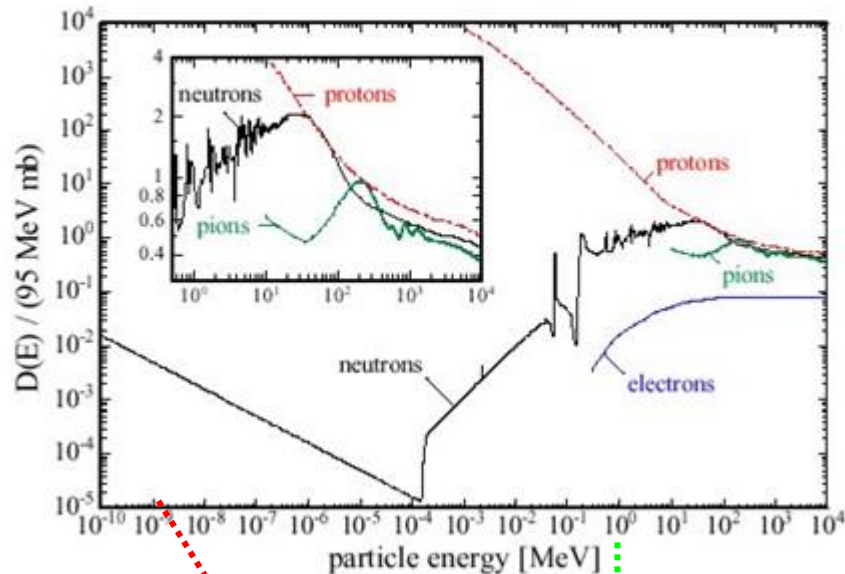


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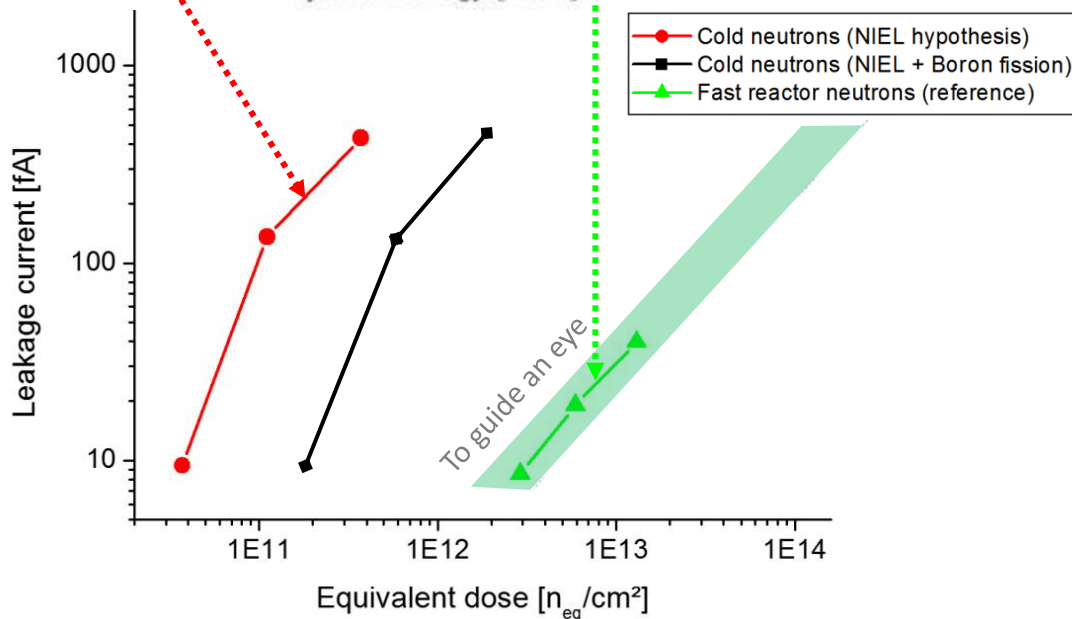


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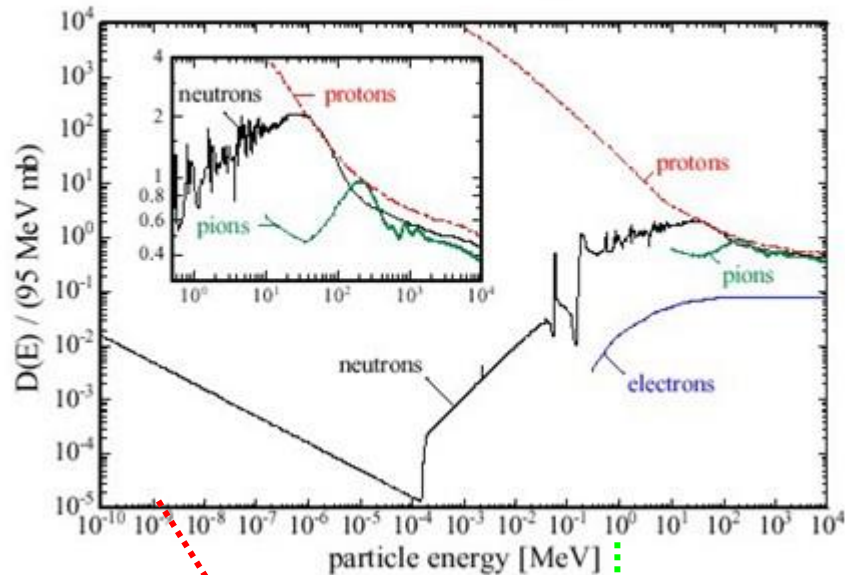


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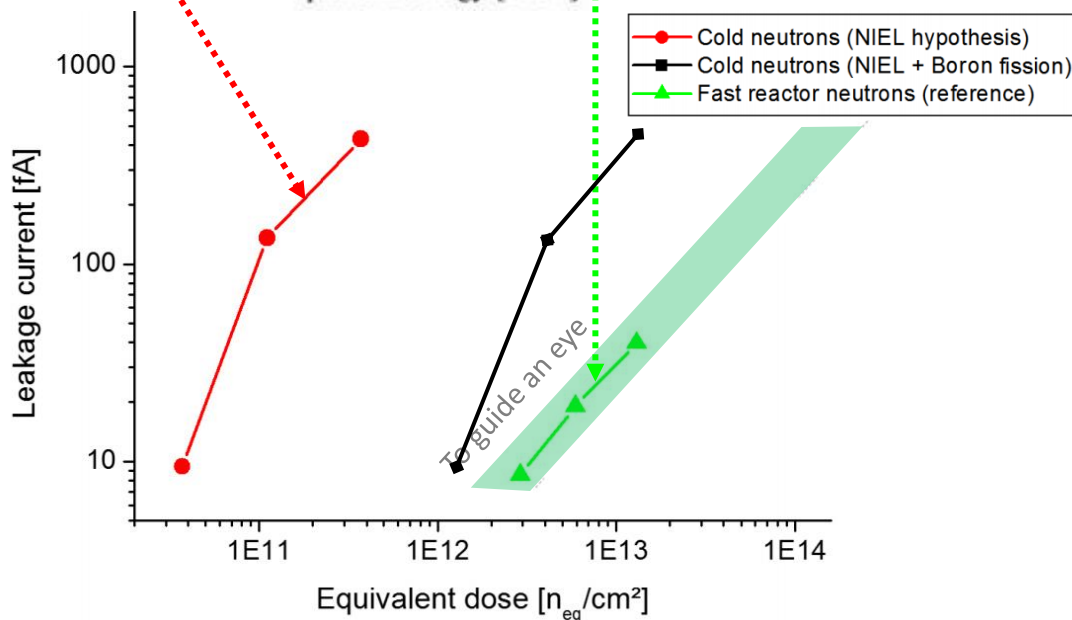


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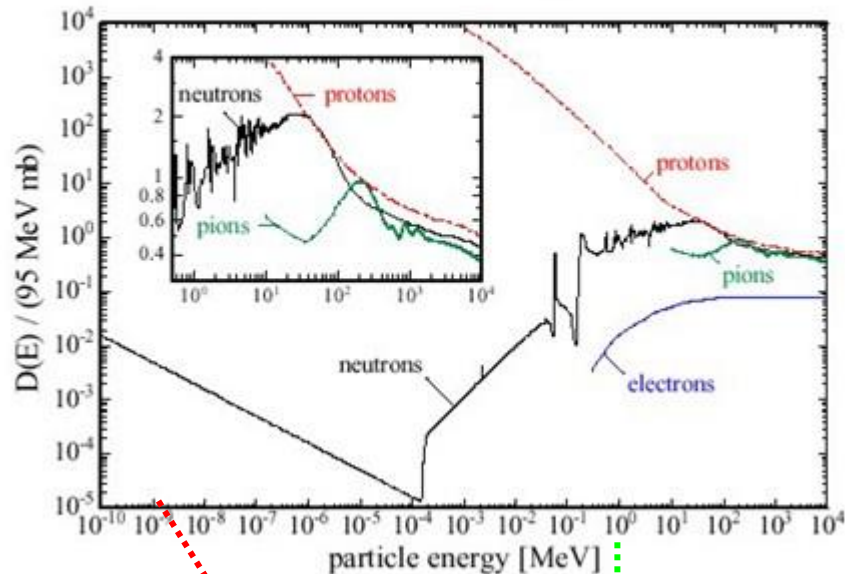


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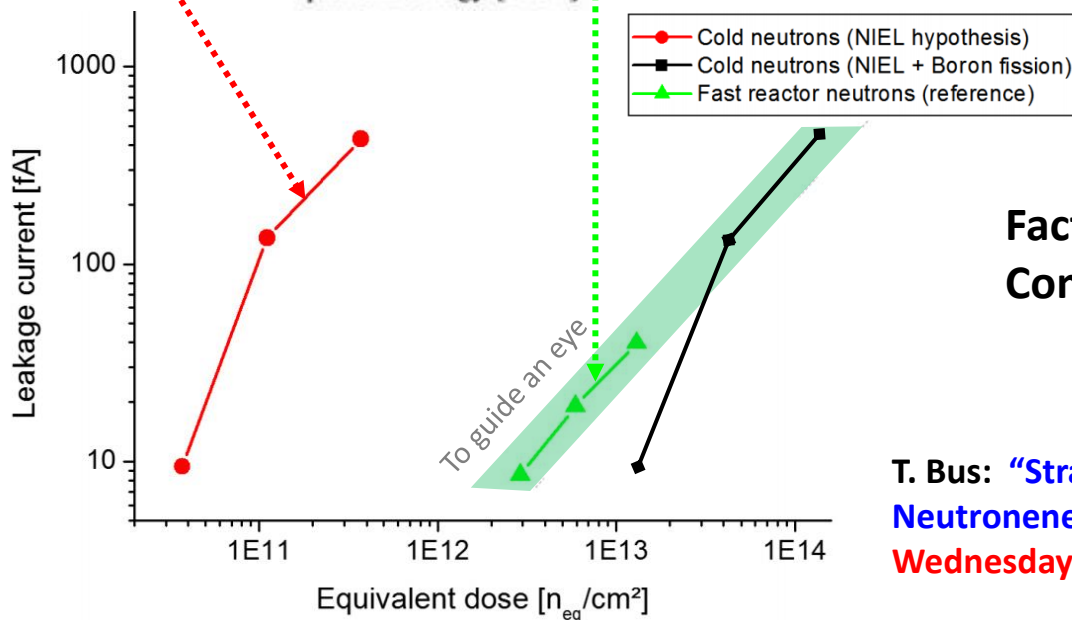


On the NIEL scaling for low-energy neutrons

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Factor of ~500 !!!

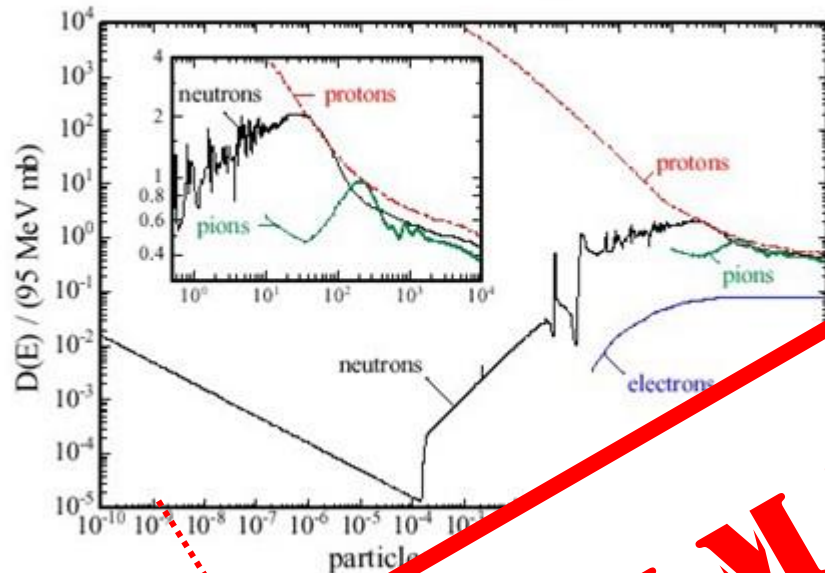
Compatible with P-doping of $10^{18}/\text{cm}^3$

T. Bus: "Strahlenschäden in dotiertem Silizium aufgrund Neutroneneinfangs Bor als Erweiterung des NIEL-Modells."

Wednesday 18:30 HK 45.49

On the NIEL scaling for low-energy neutrons

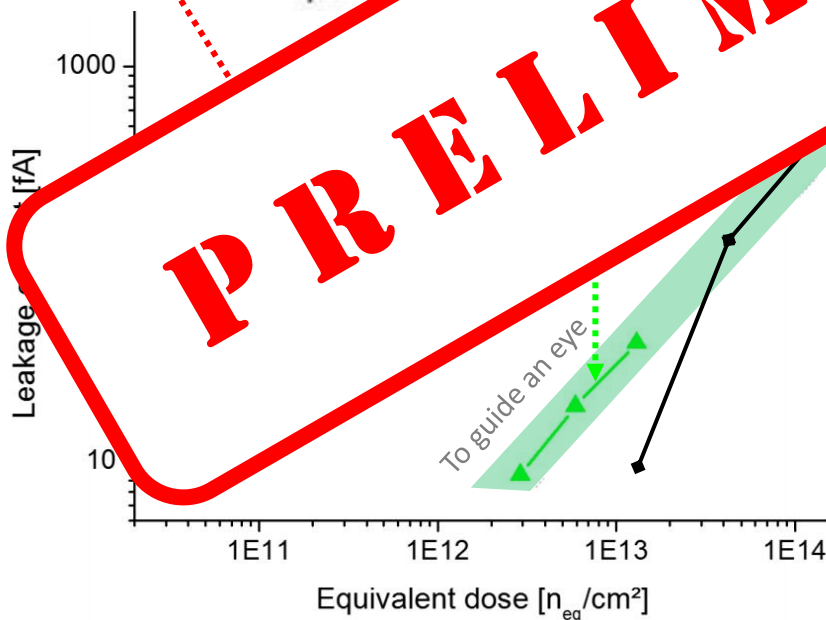
Displacement damage functions



According to NIEL (non-ionizing energy loss) scaling, any particle produced to an equivalent product specific

on the bulk damage is energy transfers to the

$\Rightarrow \text{Li} + \alpha + 3\text{MeV}$



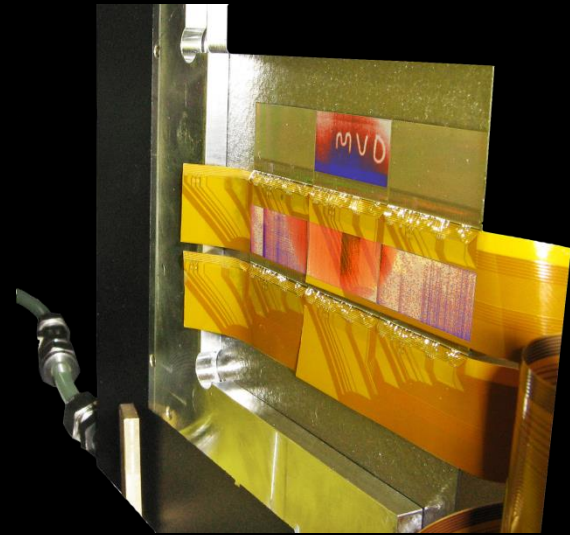
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Wednesday 18:30 HK 45.49

PRESTO Project



P. Klaus, M. Wiebusch et al., “Prototyping the read-out chain of the CBM Micro Vertex Detector”

Accepted for publication



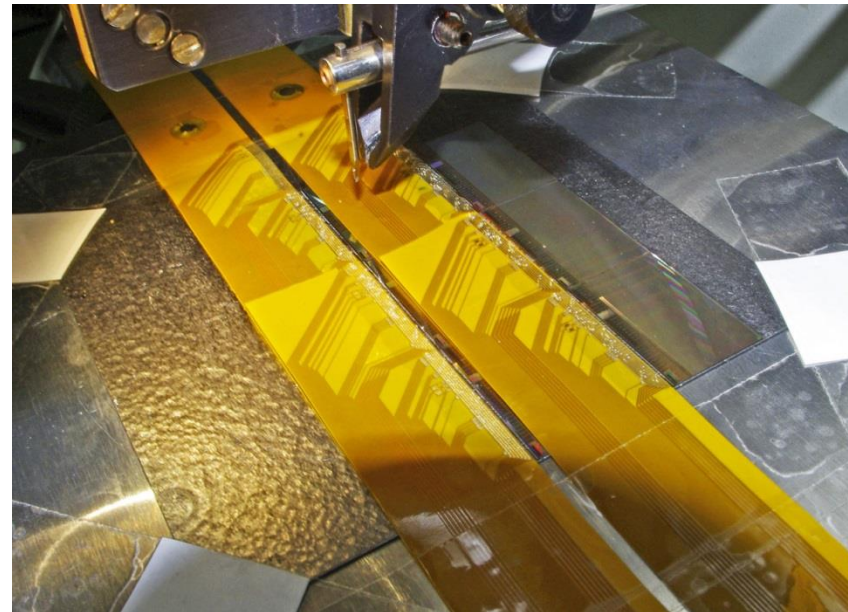
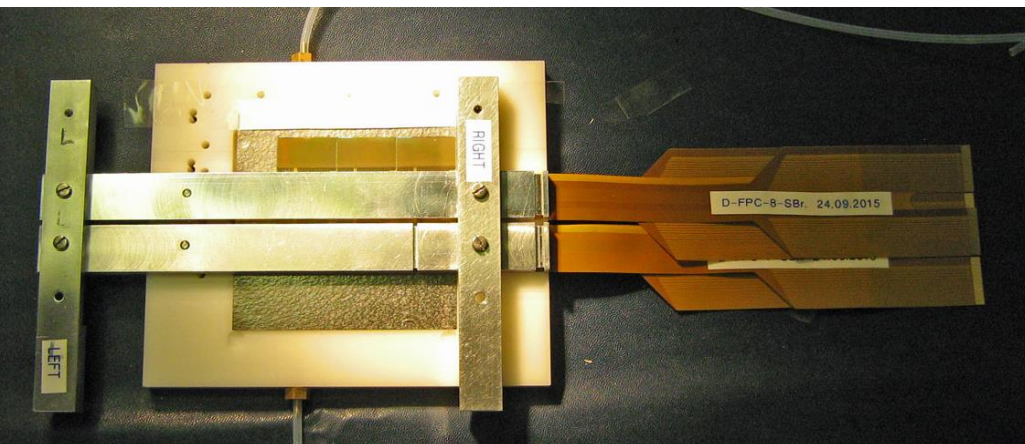
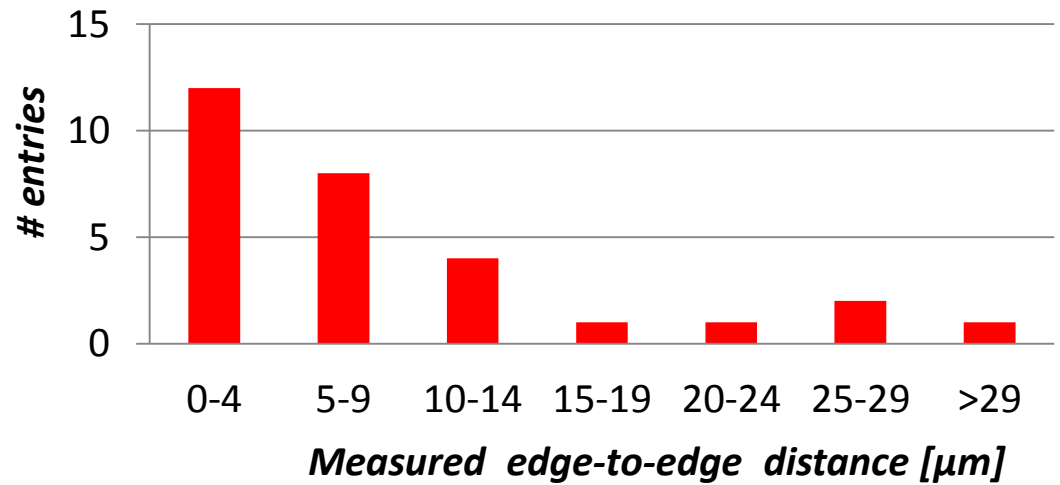
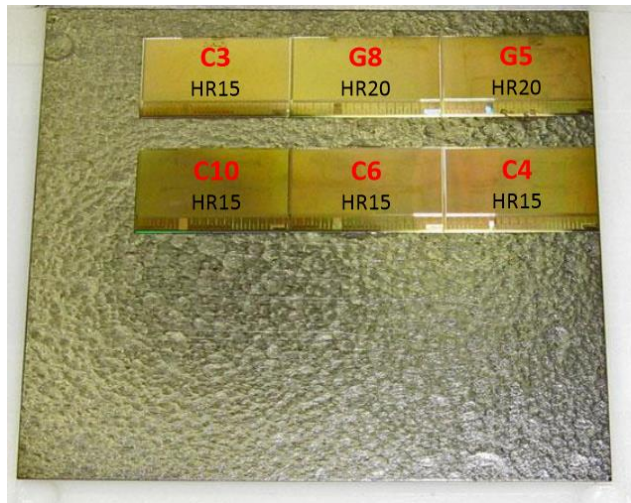
M. Koziel et al., “Vacuum-Compatible, Ultra-Low Material Budget Micro Vertex Detector of the Compressed Baryonic Matter Experiment at FAIR”

In preparation

P. Klaus: “Thin and Reliable Connectivity for the CBM-MVD”

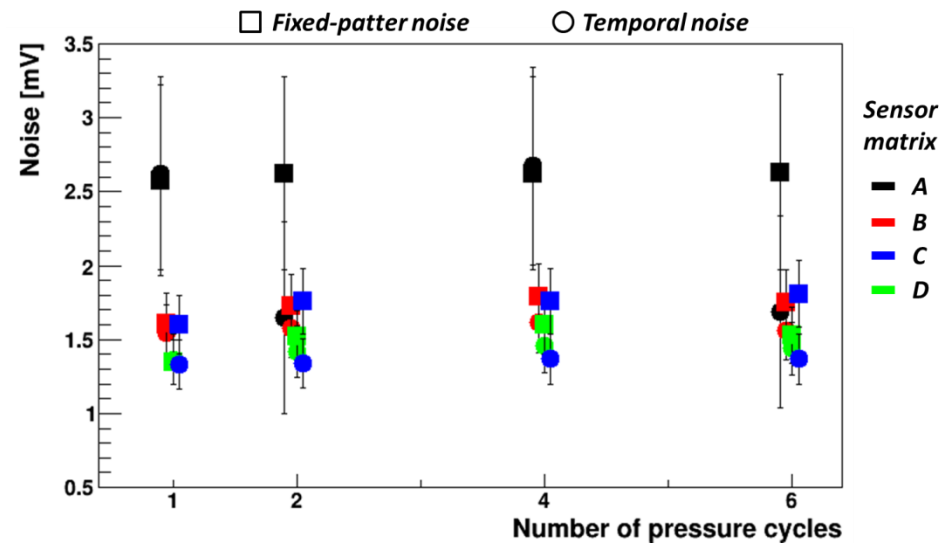
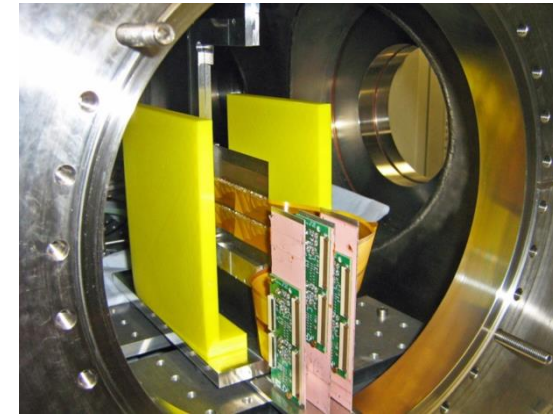
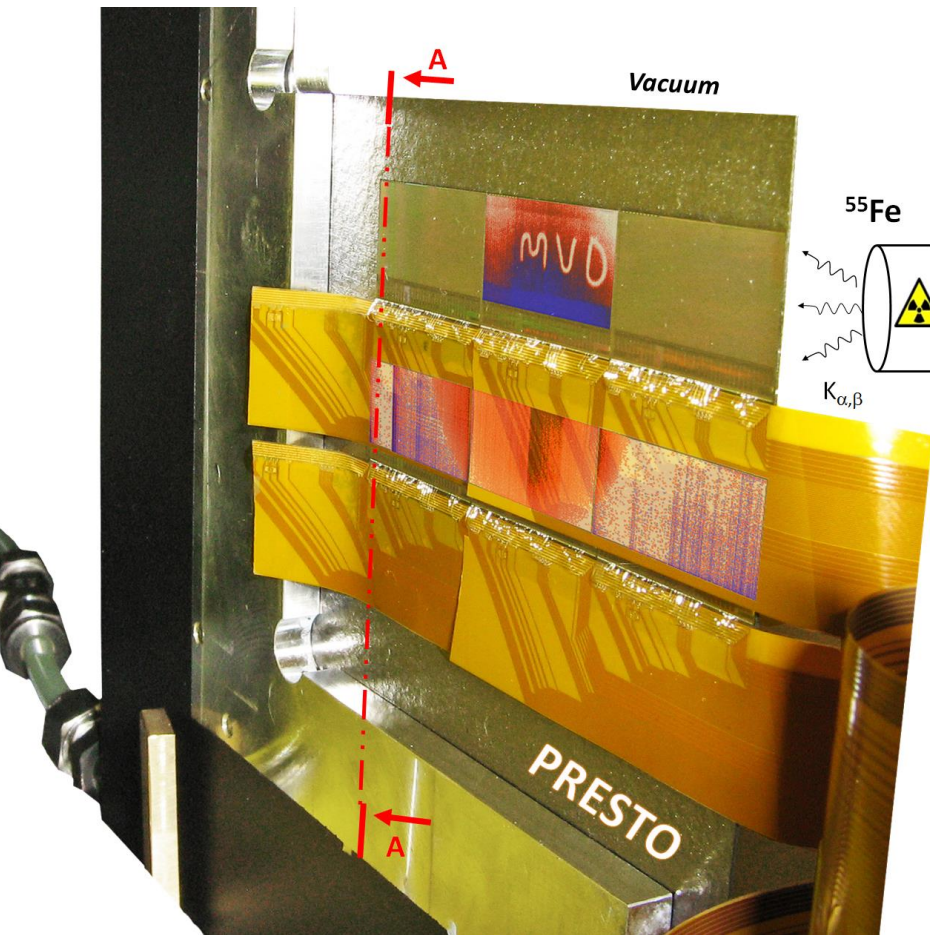
Thursday 18:00 HK 60.7

PRESTO: construction



PRESTO: vacuum compatibility

Cooltec®
Heat-sink



**No change in sensor performance after several pressure cycles
(atmospheric – 10^{-4} mbar)**

Accomplished MVD-related PhDs: 2015



Dennis Doering

“Untersuchungen zur Verbesserung der Strahlenhärte von CMOS-Sensoren zum Einsatz in Vertexdetektoren von Schwerionenexperimenten.”



Tobias Tischler

“Mechanical Integration of the Micro Vertex Detector for the CBM experiment.”



Borislav Milanovic

“Development of the Readout Controller for the CBM Micro Vertex Detector.”



SUMMARY:

- Wide range of activities towards the CBM-MVD
- PRESTO project
 - proves that one can built a vacuum compatible device based on a bare TPG carrier and employing ultra-thin, but industrial flex cable.
 - Construction of the second side is ongoing (last R&D step before MVD production)
- MVD: flexibility to adopt to physics case
- Sensors implemented in Jazz-Tower CMOS process seems to meet radiation tolerance requirements
- Technical specification of the MVD sensor in advance stage, synergy with other experiments, mainly STAR (running!) and ALICE upgrade

*Thank you for
your attention...*

